

INTERNATIONAL STANDARD

**Medical diagnostic X-ray equipment - Radiation conditions for use in the
determination of characteristics**

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CONTENTS

FOREWORD	4
INTRODUCTION	6
1 Scope	7
2 Normative references	7
3 Terms and definitions	7
3.1 Terms defined in this document	7
3.2 Terms defined in other standards	8
4 Common aspects	16
4.1 X-ray radiation conditions	16
4.2 Test instrumentation	16
4.2.1 Maximum inherent filtration	16
4.2.2 Anode material	16
4.2.3 Percentage ripple of the X-ray tube voltage	16
4.2.4 X-ray tube voltage adjustment	16
4.2.5 X-ray tube voltage measuring device	17
4.2.6 Radiation detector	17
4.2.7 Measuring arrangements	17
5 RQR X-ray radiation conditions	17
5.1 Object	17
5.2 Characterization	17
5.3 Description	17
5.4 Additional filtration	18
5.5 Test equipment	18
5.5.1 Auxiliary filter	18
5.5.2 Attenuation layers	18
5.5.3 Diaphragm	19
5.5.4 Radiation detector	19
5.5.5 X-ray tube voltage measuring device	19
5.6 Generation and verification	19
5.6.1 Geometry	19
5.6.2 RQR X-ray radiation conditions	19
5.6.3 Series of RQR X-ray radiation conditions	19
6 RQA X-ray radiation conditions	20
6.1 Object	20
6.2 Characterization	20
6.3 Description	20
6.4 Added filter	21
6.5 Generation and verification	21
6.5.1 RQA X-ray radiation conditions	21
6.5.2 Alternative method	21
7 RQC X-ray radiation conditions	22
7.1 Object	22
7.2 Characterization	22
7.3 Description	22

7.4	Added filter	22
7.5	Generation and verification	23
8	RQT X-ray radiation conditions	23
8.1	Object	23
8.2	Characterization	23
8.3	Description	23
8.4	Added filter	24
8.5	Generation and verification	24
8.5.1	RQT X-ray radiation conditions	24
8.5.2	Alternative method	24
9	RQN X-ray radiation conditions	24
9.1	Object	24
9.2	Characterization	24
9.3	Description	25
9.4	Phantom	25
9.5	Diaphragms	25
9.6	Generation	25
10	RQB X-ray radiation conditions	26
10.1	Object	26
10.2	Characterization	26
10.3	Description	26
10.4	Phantom	26
10.5	Diaphragms	27
10.6	Generation	27
11	RQR-M X-ray radiation conditions	27
11.1	Object	27
11.2	Characterization	27
11.3	Description	27
11.4	Generation and verification	28
12	RQA-M X-ray radiation conditions	28
12.1	Object	28
12.2	Characterization	28
12.3	Description	28
12.4	Generation	29
13	RQN-M X-ray radiation conditions	29
13.1	Object	29
13.2	Characterization	29
13.3	Description	29
13.4	Phantom	30
13.5	Diaphragms	30
13.6	Generation	30
14	RQB-M X-ray radiation conditions	30
14.1	Object	30
14.2	Characterization	31
14.3	Description	31
14.4	Phantom	31
14.5	Diaphragm	32
14.6	Generation	32

Annex A (normative) Measuring arrangements	33
Annex B (informative) Determination of the amount of additional filtration.....	39
Annex C (informative) Tabulated values for the squared signal-to-noise ratio per air kerma (SNR_{in2})	40
Annex D (normative) Additional X-ray radiation conditions as used in mammography and determination of the corresponding nominal aluminium half-value layers	41
D.1 Object	41
D.2 Characterization	41
D.3 Description	41
D.4 Generation and verification	41
Annex E (informative) Overview of X-ray radiation conditions	43
Bibliography	44
Figure A.1 – Measuring arrangement for achieving RQR 2 to RQR 10 X-ray radiation conditions	33
Figure A.2 – Measuring arrangement for achieving RQA 2 to RQA 10 X-ray radiation conditions	34
Figure A.3 – Measuring arrangement for achieving RQN 2 to RQN 10 X-ray radiation conditions	35
Figure A.4 – Measuring arrangement for achieving RQB 2 to RQB 10 X-ray radiation conditions	36
Figure A.5 – Measuring arrangement for achieving RQN-M X-ray radiation conditions	37
Figure A.6 – Measuring arrangement for achieving RQB-M X-ray radiation conditions	38
Figure B.1 – Determination of additional filtration required for adjusting the total filtration to the prescribed value (see 5.4).	39
Table 1 – Parameters for RQR 2 to RQR 10 X-ray radiation conditions	18
Table 2 – Parameters for RQA 2 to RQA 10 X-ray radiation conditions	21
Table 3 – Parameters for RQC 3, RQC 5 and RQC 8 X-ray radiation conditions	22
Table 4 – Parameters for RQT 8, RQT 9 and RQT 10 X-ray radiation conditions	23
Table 5 – Parameters for RQR-M 1 to RQR-M 4 X-ray radiation conditions	28
Table 6 – Parameters for RQA-M 1 to RQA-M 4 X-ray radiation conditions	29
Table 7 – Parameters for RQN-M 1 to RQN-M 4 X-ray radiation conditions	30
Table 8 – Parameters for RQB-M 1 to RQB-M 4 X-ray radiation conditions	31
Table C.1 – SNR_{in2} values for the RQA X-ray radiation conditions	40

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Medical diagnostic X-ray equipment - Radiation conditions for use in the determination of characteristics

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